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Analog Integrated Circuit Optimization Using Spice Francesc Serra-Graells¹, Arantxa Uranga² and Núria Barniol²

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INTRODUCTION

This paper proposes a training strategy based on Spice simulation to teach analog integrated circuit optimization. The choice of the Spicelanguage standard ensures the applicability of the acquired knowledge in most of the analog design fields for SoCs (e.g. signal processing, RF communications, power control). In this sense, the Spice Opus CAD tool [1] have been selected here, which is a free Berkeley Spice3 compliant simulator with optimization and XSpice [2] mixed-mode capabilities, so it can be also reused for other related syllabus like fullcustom design [3] or mixed modelling [4].

AUTOMATIC CHARACTERIZATION 3

The next step towards the cell optimization is the automatic extraction of its performance. The challenge for the student in this stage is both, to perform several analysis in different test circuits and to program the automatic measurements to be applied to the simulation results, like:

.control source qopenloop.sp3 source follower.sp3 setcirc qopenloop.sp3 let pd=-i(vdd)*v(vdd)*1e3let area=(@m1:xopamp[w]+6u)*(@m1:xopamp[1]+11u)+(@m2:xopamp[w]+6u)*(@m2... ac dec 50 10 10e6 let gmag=20*log10(mag(v(vout))) let gph=phase(v(vout))

TEST CIRCUITS

The practice example presented is built around the classic dualstage Miller operational amplifier of Figure 1(left). In this case, the main specifications are: differential voltage gain at DC (gdc), gain-bandwidth product (gbw), phase margin (pm), slew-rate +/-(srpos/srneg), Si circuit area (area) and power consumption (pd). The first step for the student is to model this cell under test in terms of a Spice subcircuit, like in Figure 1(right). As any CMOS circuit, the basic design variables are the device dimensions (i.e. w and 1) and bias, which in fact are related to the specifications area and pd, respectively.

 V_{DD} ϕ M7M8 V_{out} ' in-M2M1 C_{comp} M9M3M4M6 V_{SS} (V_{in+}

.subckt opamp vinn vinp vout vdd vss ml vload vinn vcomm vdd modp w=18u l=6u m2 vinter vinp vcomm vdd modp w=18u l=6u m3 vload vload vss vss modn w=12u l=12u m4 vinter vload vss vss modn w=12u l=12u m5 vout vbias vdd vdd modp w=96u l=6u m6 vout vinter vss vss modn w=48u l=6u m7 vcomm vbias vdd vdd modp w=24u l=6u m8 vbias vbias vdd vdd modp w=12u l=6u m9 vbias vbias vss vss modn w=3u l=24u ccomp vout vinter cpoly w=100u l=100u .ends

let gdc=gmag[0] let gbw=abs(frequency[sum(gmag ge 0)])/1e6 let pm=180+gph[sum(gmag ge 0)] setcirc follower.sp3 tran 1n 5u let vrise=v(vout)*(time lt 3u)+3*(time ge 3u) let trisebot=min(time*(vrise ge 2.1)+(vrise lt 2.1)) let trisetop=min(time*(vrise ge 2.9)+(vrise lt 2.9)) let srpos=0.8/(trisetop-trisebot)*1e-6 let vfall=v(vout)*(time ge 3u)+3*(time lt 3u) let tfalltop=min(time*(vfall lt 2.9)+(vfall ge 2.9)) let tfallbot=min(time*(vfall lt 2.1)+(vfall ge 2.1)) let srneg=0.8/(tfallbot-tfalltop)*1e-6 .endc

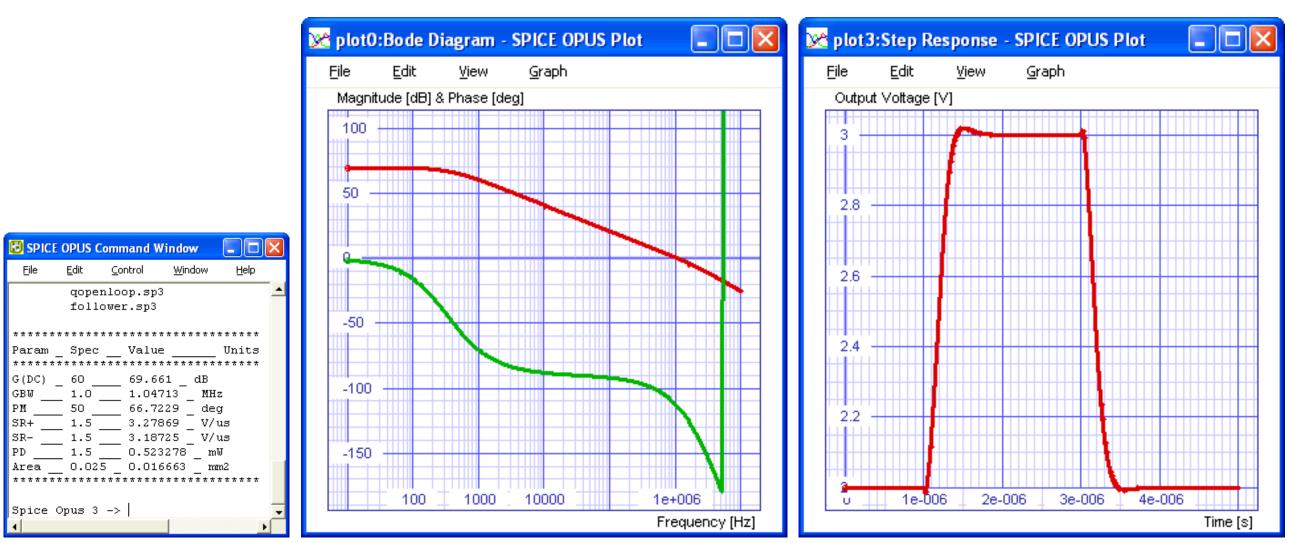
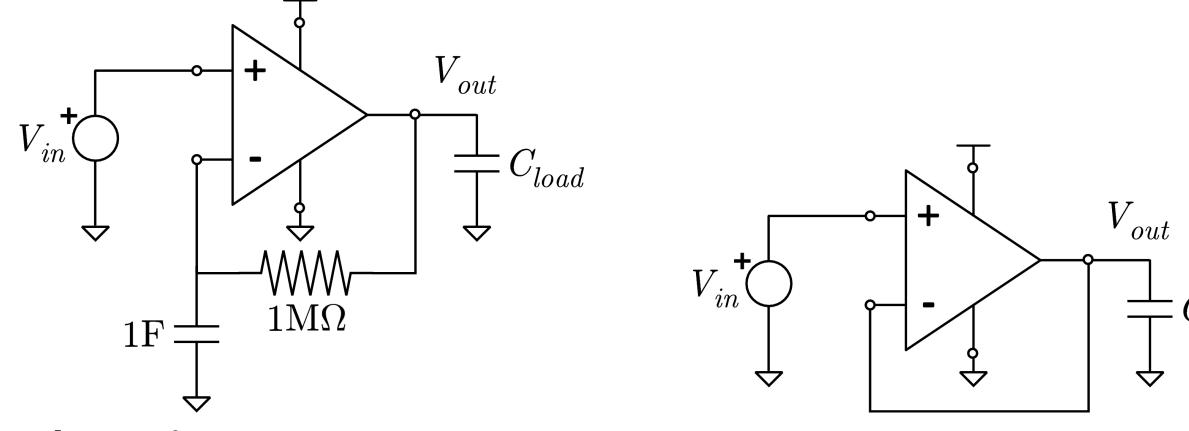


Fig. 3. Simulation results (center and right), and datasheet (left) after automatic extraction of Figure 1.

Fig. 1. Operational amplifier under test (left) and equivalent Spice sub-circuit (right).

In order to cover all the required specifications, the student has to manage with several test circuits around the cell. A good solution in this case is the double test set-up shown in Figure 2.



qopenloop.sp3 .include cnm25typ.mod2 .include opamp.sp3 cload vout 0 10p vin vin 0 dc=2.5v ac=1 xopamp vfb vin vout vdd vss opamp vss vss 0 dc=0v vdd vdd 0 dc=5vcdc vfb 0 1 rdc vfb vout 1000k .end

follower.sp3 .include cnm25typ.mod2 .include opamp.sp3 cload vout 0 10p vin vin 0 pulse(2 3 lu ln ln 2u) xopamp vout vin vout vdd vss opamp vss vss 0 dc=0v vdd vdd 0 dc=5v.end

- C_{load}

Fig. 2. Quasi open-loop (left) and follower (right) test circuits.

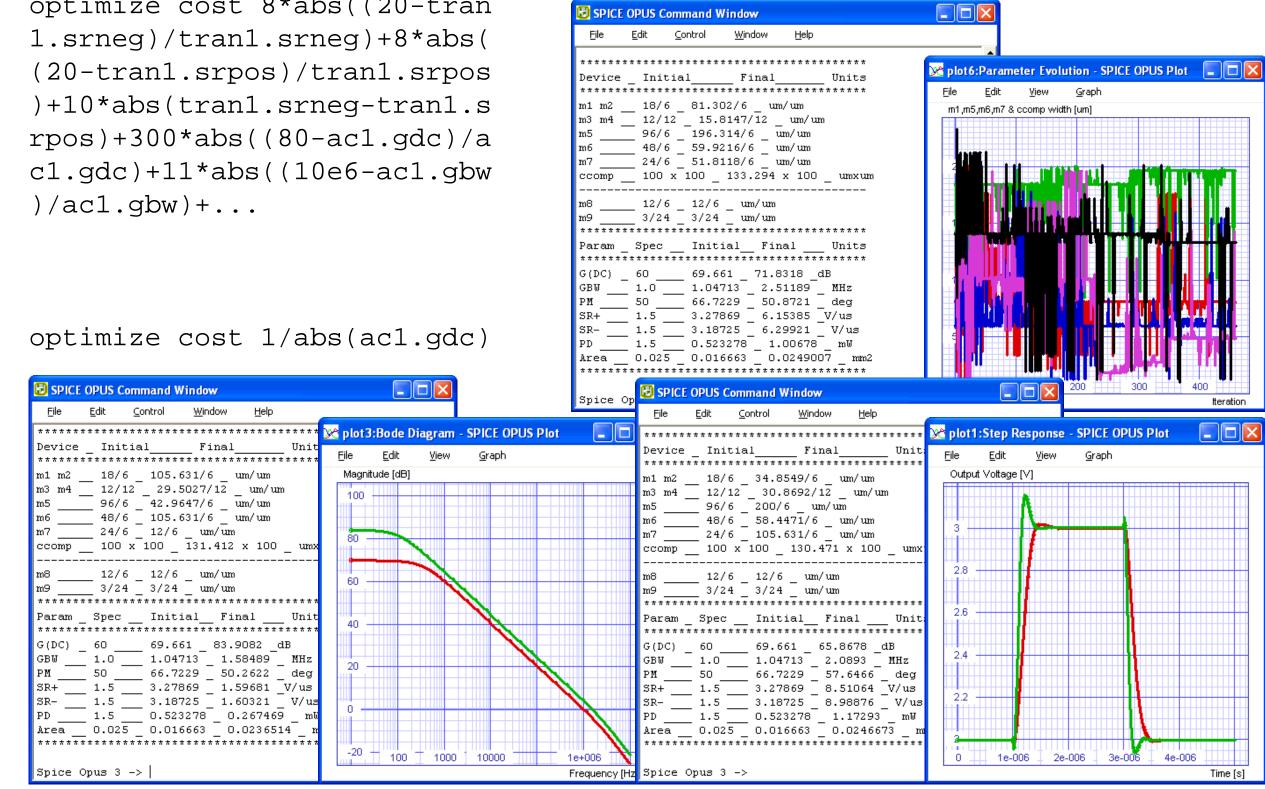
OPTIMIZATION PROCESS 4

Its definition involves the declaration of the design variables, the required analysis, the implicit constraints, and the cost function. In this sense, the student should minimize the number of design variables by, for example, exploiting circuit symmetries. Also, proper ranges and initial values should be derived from the analytical design equations:

optimize parameter 0 element ml:xopamp parameter w low 12u high 200u initial 12u optimize parameter 1 element m5:xopamp parameter w low 12u high 200u initial 96u optimize analysis 0 setcirc qopenloop.sp3 optimize analysis 1 op optimize implicit 0 op1.pd lt 1.5 optimize implicit 1 op1.area lt 0.025

Finally, but most important, the success of any optimization process is not only given by the algorithm itself but also by the cost function, which classifies the solution obtained in each iteration. At this point, students can experiment with a wide variety of expressions:

optimize cost 8*abs((20-tran 1.srneg)/tran1.srneg)+8*abs((20-tran1.srpos)/tran1.srpos)+10*abs(tran1.srneg-tran1.s rpos)+300*abs((80-ac1.gdc)/a



CONCLUSIONS 5

The main advantages of the proposed training methodology for analog integrated circuit optimization are: full control of all steps by the student, standard language scripting, high flexibility, applicability to a wide range of analog integrated circuits, and free CAD tools.

REFERENCES

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[3] F. Serra-Graells and N. Barniol, *Design of Analogue*

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optimize cost 1/abs(tran1.srneg)+1/abs(tran1.srpos)+1000*abs(op1.pd-1.5)

Fig. 4. Cost function examples and results for both, global (upper) and specific (lower) optimizations.